

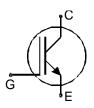
IGBT³ Chip

SIGC57T120R3

FEATURES:

- 1200V Trench + Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

- This chip is used for:
- power module
- **Applications:**
- drives



Chip Type	V _{CE}	I Cn	Die Size	Package	Ordering Code	
SIGC57T120R3	1200V	50A	7.6 x 7.53 mm ²	sawn on foil	Q67050- A4106-A001	

MECHANICAL PARAMETER:

Raster size	7.6 x 7.53	mm	
Emitter pad size	4x(2.98 x 2.97)		
Gate pad size	1.139 x 1.139		
Area total / active	57.2 / 42.8	mm ²	
Thickness	140	μm	
Wafer size	150	mm	
Flat position	90	grd	
Max.possible chips per wafer	246 pcs		
Passivation frontside	Photoimide		
Emitter metallization	3200 nm AlSiCu		
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	electrically conductive glue or solder		
Wire bond	Al, <500µm		
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm		
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C		



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, Tj=25 °C	V _{CE}	1200	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t_p limited by T_{jmax}	I _{cpuls}	150	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
	Cymbol	Conditions	min.	typ.	max.	•
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I _C = 2mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =50A	1.4	1.7	2.1	V
Gate-emitter threshold voltage	V _{GE(th)}	$I_C=2mA$, $V_{GE}=V_{CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			6.79	μA
Gate-emitter leakage current	I _{GES}	$V_{CE}=0V$, $V_{GE}=20V$			600	nA
Integrated gate resistor	R _{Gint}			4		Ω

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
Falameter	Symbol	Conditions	min.	typ.	max.	Unit
Input capacitance	Ciss	V _{CE} =25V,		3600		pF
Output capacitance	Coss	$V_{GE}=0V$,		188		
Reverse transfer capacitance	Crss	<i>f</i> =1MHz		163		

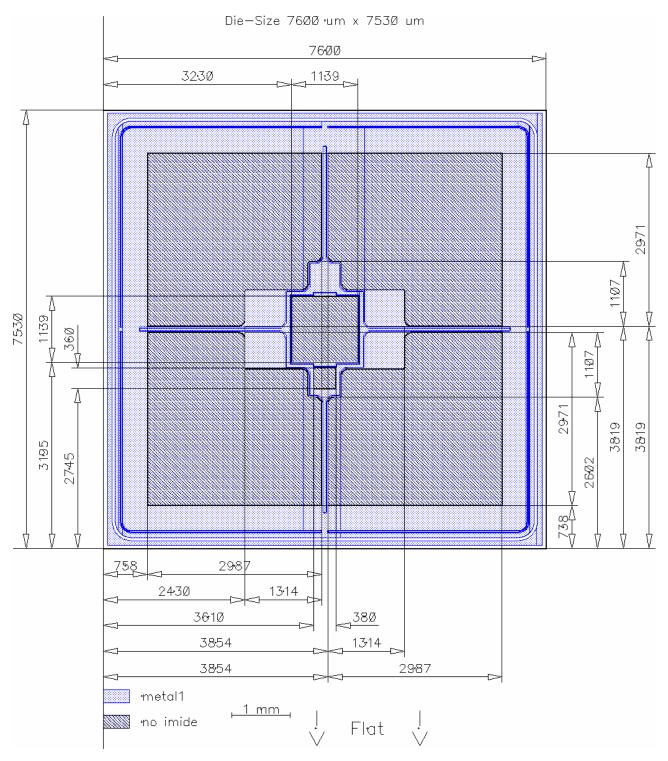
SWITCHING CHARACTERISTICS (tested at component), Inductive Load

Parameter	Symbol	Conditions ¹⁾	Value			Unit
T diameter	Oymbol		min.	typ.	max.	
Turn-on delay time	t _{d(on)}	<i>T</i> _j =125°C		90		ns
Rise time	<i>t</i> r	$V_{\rm CC} = 600 V$,		45		
Turn-off delay time	$t_{d(off)}$	V _{GE} =-15/15V,		520		
Fall time	t _f	R _G = 18Ω		90		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the	tbd	
device data sheet		

DESCRIPTION:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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